

General Description

The MDW1304E uses advanced MagnaChip's MOSFET Technology, which provides high performance in on-state resistance, high switching performance and excellent reliability. Excellent low $R_{DS(ON)}$, low gate charge operation and operation for Battery Application.

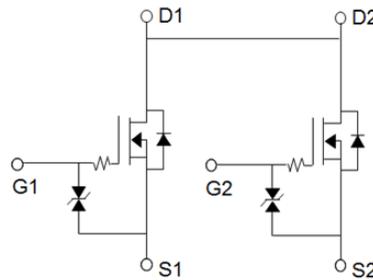
Features

- $V_{DS} = 24V$
- Drain-Source ON Resistance;
 $R_{DS(ON)} < 40m\Omega @ V_{GS} = 3.0V$
 $R_{DS(ON)} < 34m\Omega @ V_{GS} = 3.9V$

Applications

- Portable Battery Protection Module
- Wearable Device Protection Module

Bottom View



Electrical Characteristics ($T_A=25^\circ C$)

Characteristics	Symbol	Test Condition	Min	Typ	Max	Units
Static Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$I_D = 500\mu A, V_{GS} = 0V$	24	-	-	V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 1mA$	0.5	1.0	1.5	
Drain Cut-Off Current	I_{DSS}	$V_{DS} = 20V, V_{GS} = 0V$	-	-	1.0	μA
Gate Leakage Current	I_{GSS}	$V_{GS} = \pm 10V, V_{DS} = 0V$	-	-	10	μA
Drain-Source Resistance	$R_{DS(ON)}$	$V_{GS} = 3.0V, I_D = 5.0A$	-	33	40	m Ω
		$V_{GS} = 3.9V, I_D = 5.0A$	-	28	34	

Mechanical Data

Contents	Configuration
Passivation	TEOS (3,000 Å) - Nitride (6,000 Å)
Back Metal Composition (Thickness)	NiV (3,000 Å) – Ag (1,500 Å)
Front Metal Composition (Thickness)	Al (45,000 Å)
Die Dimension (with S/L)	1,240 μm x 845 μm
Gate Pad Dimension	120 μm x 120 μm
Wafer Diameter	200 mm, with 100 flat
Wafer Thickness	145 μm
Scribe lane width	60 μm

Electrical Characteristics (T_A =25°C unless otherwise noted)

Characteristics	Symbol	Test Condition	Min	Typ	Max	Units
Static Characteristics						
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Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 1mA	0.5	1.0	1.5	
Drain Cut-Off Current	I _{DSS}	V _{DS} = 20V, V _{GS} = 0V	-	-	1.0	μA
Gate Leakage Current	I _{GSS}	V _{GS} = ±10V, V _{DS} = 0V	-	-	10	μA
Drain-Source Resistance ^{Note 2}	R _{DS(on)}	V _{GS} = 3.0V, I _D = 5.0A	-	33	40	mΩ
		V _{GS} = 3.9V, I _D = 5.0A	-	28	34	
Forward Transconductance	g _{fs}	V _{DS} = 5V, I _D = 5A	-	9.5	-	S
Dynamic Characteristics ^{Note 3}						
Total Gate Charge	Q _g	V _{DS} = 12V, I _D = 5.0A, V _{GS} = 4.5V, I _G = 1mA	-	10.3	-	nC
Gate-Source Charge	Q _{gs}		-	3.9	-	
Gate-Drain Charge	Q _{gd}		-	3.9	-	
Input Capacitance	C _{iss}	V _{DS} = 12V, V _{GS} = 0V, f = 1MHz	-	525	-	pF
Reverse Transfer Capacitance	C _{rss}		-	195	-	
Output Capacitance	C _{oss}		-	223	-	
Turn-On Delay Time	t _{d(on)}	V _{GS} = 4.5V, V _{DS} = 12V, I _D = 5A, R _G = 6 Ω	-	0.08	-	us
Rise Time	t _r		-	2.2	-	
Turn-Off Delay Time	t _{d(off)}		-	0.6	-	
Fall Time	t _f		-	0.4	-	
Drain-Source Body Diode Characteristics ^{Note 3}						
Source-Drain Diode Forward Voltage	V _{SD}	I _S = 3.0A, V _{GS} = 0V	-	0.75	1.0	V

Notes :

- The device current rating is derived from its thermal resistance and from the number and diameter of bonding wires.
The testing current at wafer level is set only for ease of testing. Actual package current ratings can be much higher.
- R_{DS(on)} is Single MOS . In this case, R_{DS(on)} is R_{SS(on)} / 2
- Dynamic Characteristics and Drain-Source Body Diode Characteristics are tested on SOIC-8L Package.

Characteristic Graph

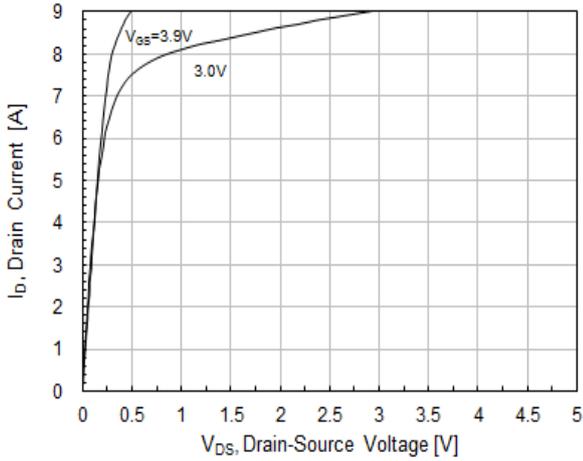


Fig.1 On-Region Characteristics

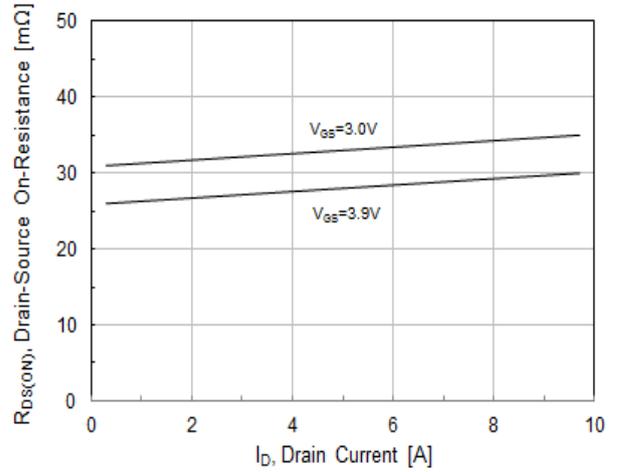


Fig.2 On-Resistance Variation with Drain Current and Gate Voltage

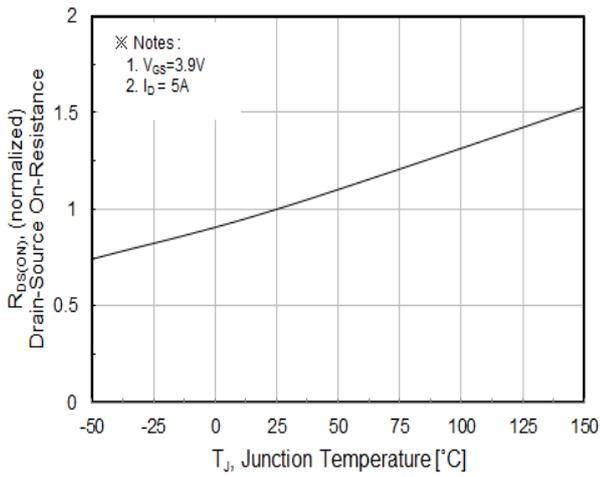


Fig.3 On-Resistance Variation with Temperature

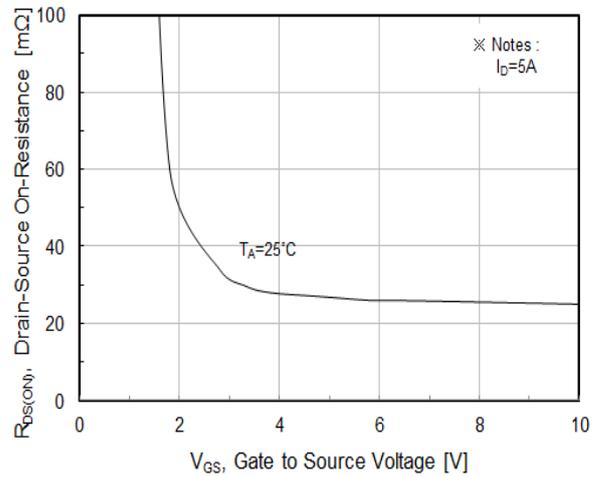


Fig.4 On-Resistance Variation with Gate to Source Voltage

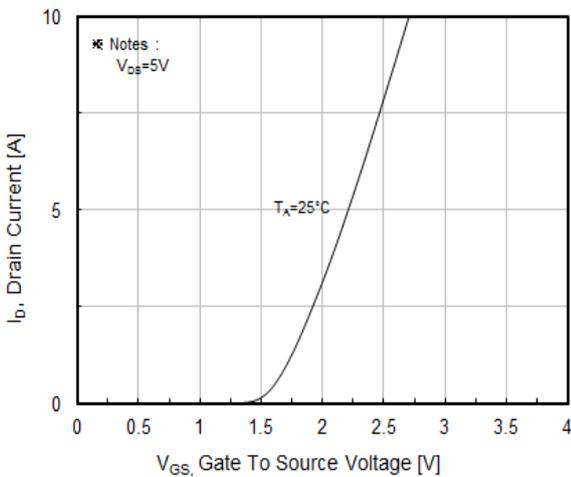


Fig.5 Transfer Characteristics

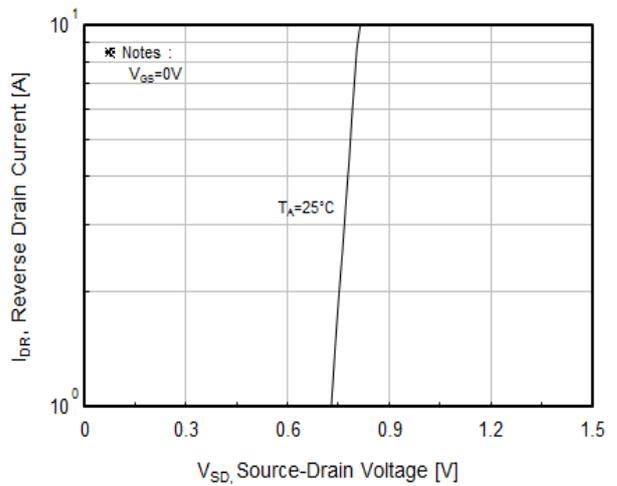


Fig.6 Body Diode Forward Voltage Variation with Source Current

Characteristic Graph

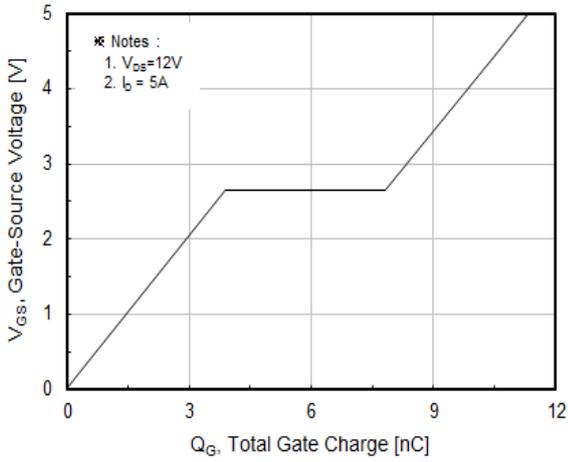


Fig.7 Gate Charge Characteristics

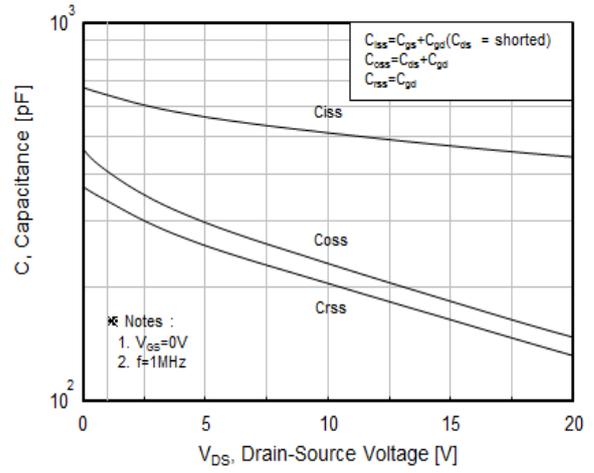


Fig.8 Capacitance Characteristics

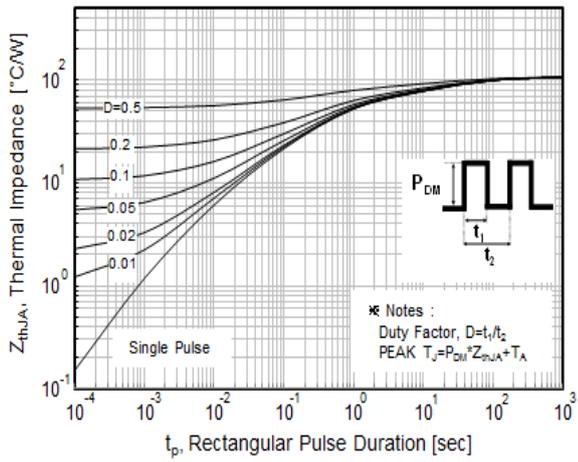


Fig.9 Transient Thermal Impedance Curve

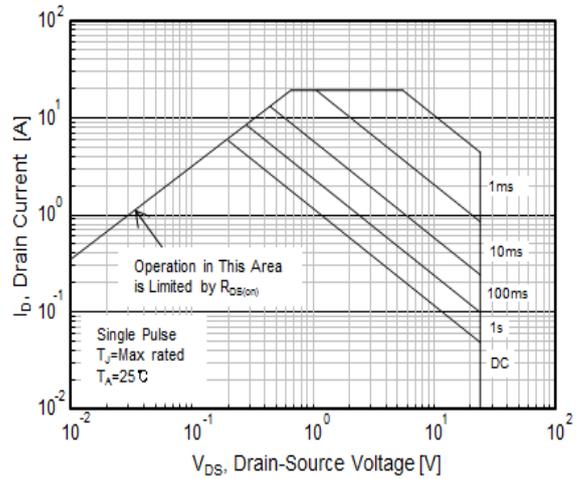
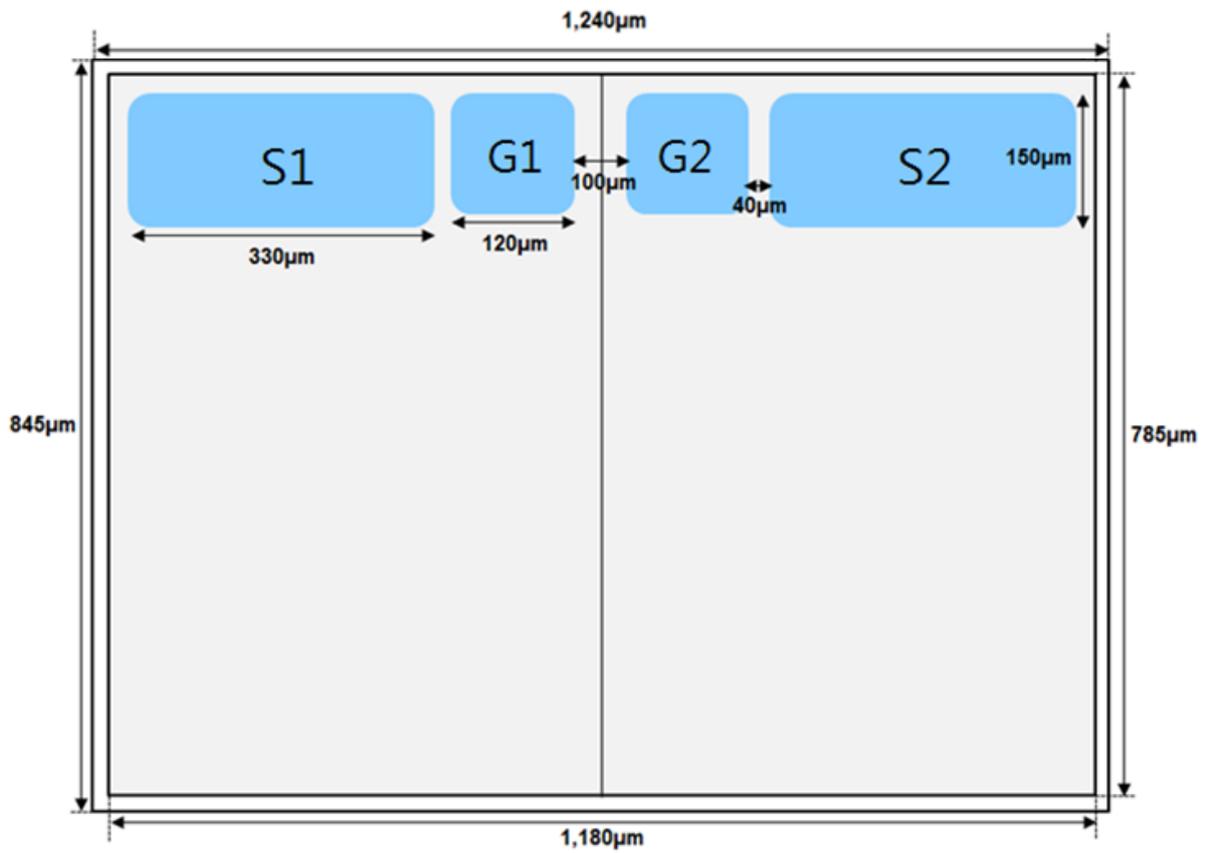


Fig.10 Maximum Safe Operating Area

Die Outline (Unit : μm)



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